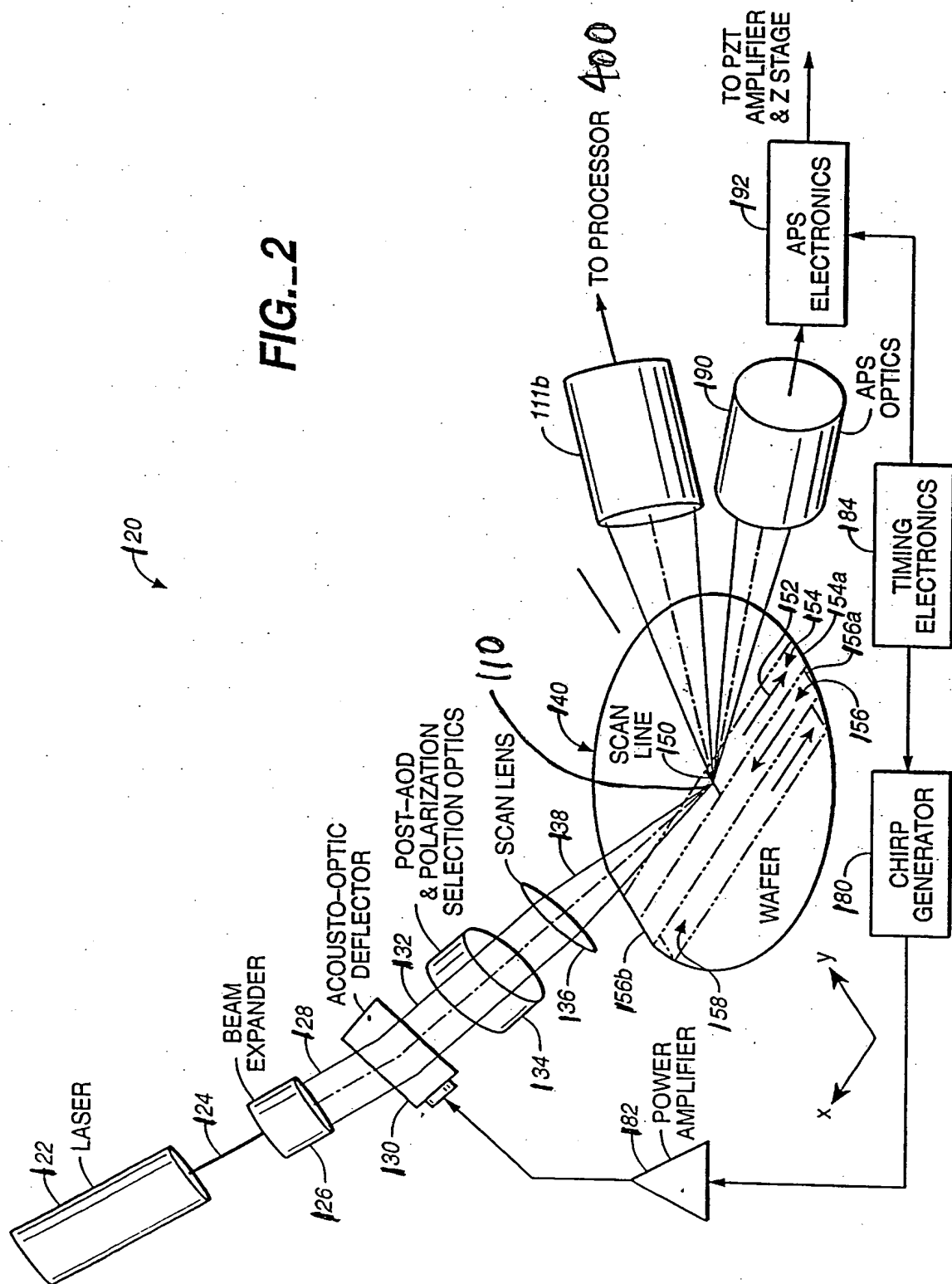
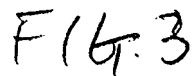


F1 G.

120





**Figure 1. Optical Pattern Filtering defect detection.**

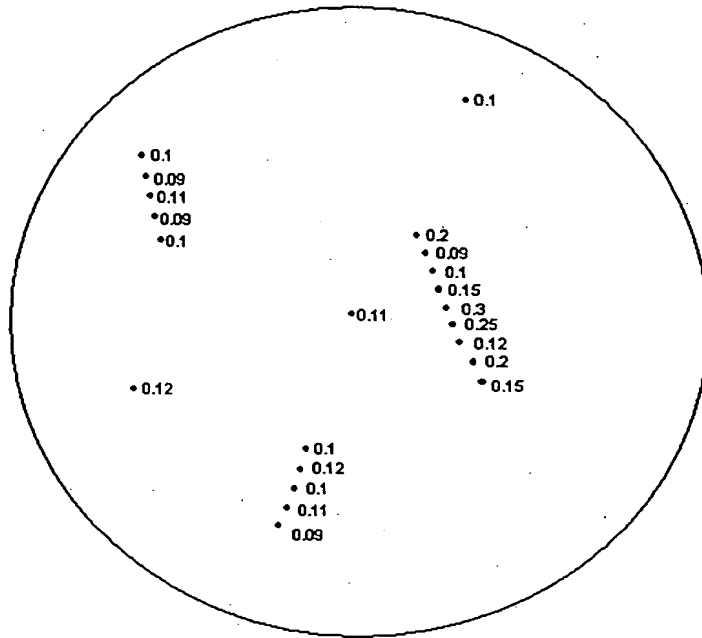


FIG. 4

Figure 2: Simulated distribution of defects after a scan. Size indicated in microns

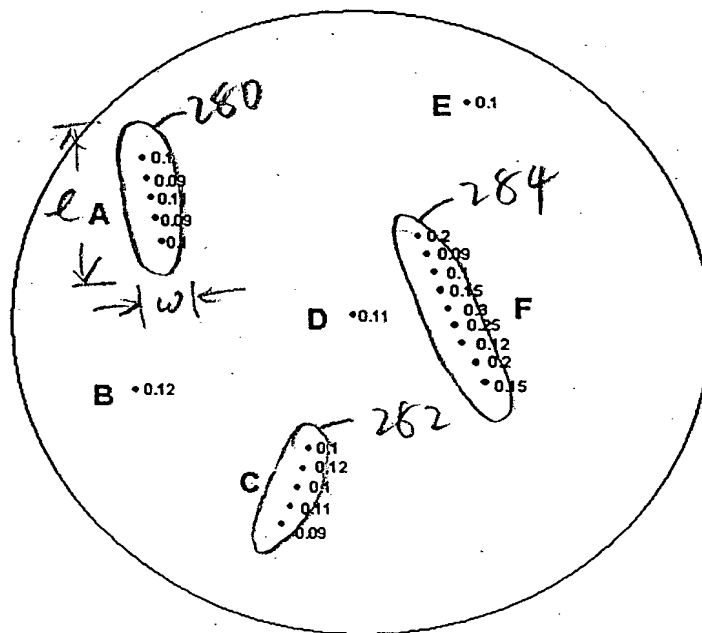


Figure 3: Initial clustering in microscratch algorithm

FIG. 5

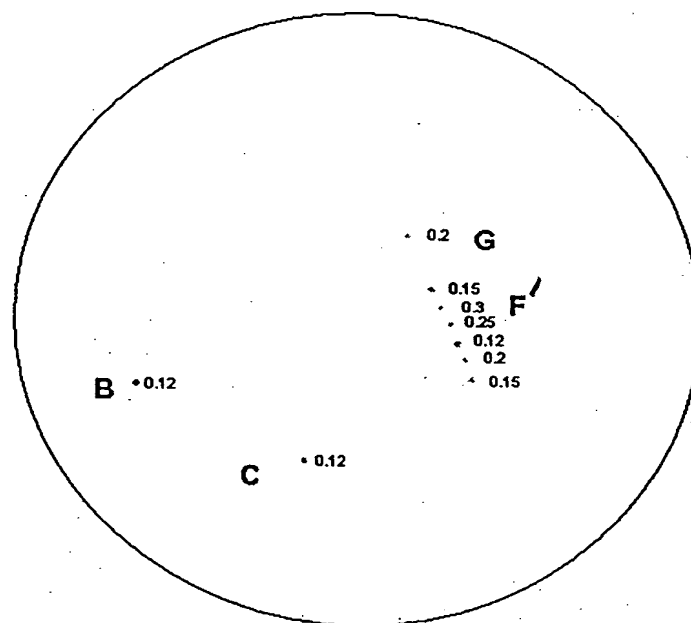


Figure 4: Final output of the microscratch algorithm.

FIG. 6

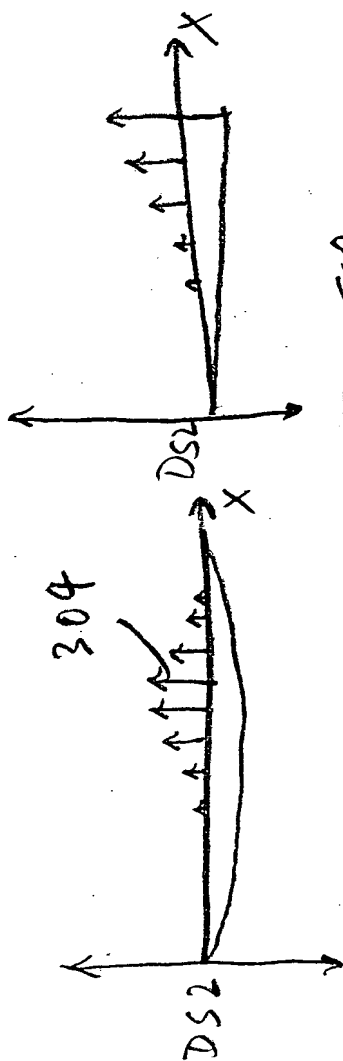


FIG. 8A

FIG. 8B

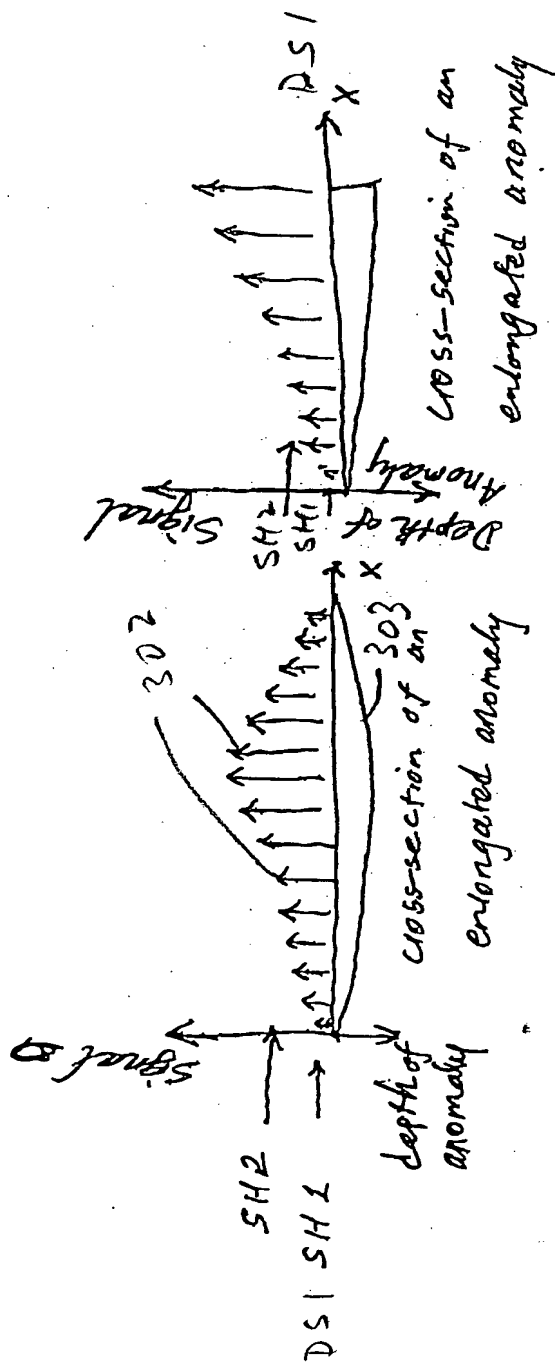


FIG. 7A

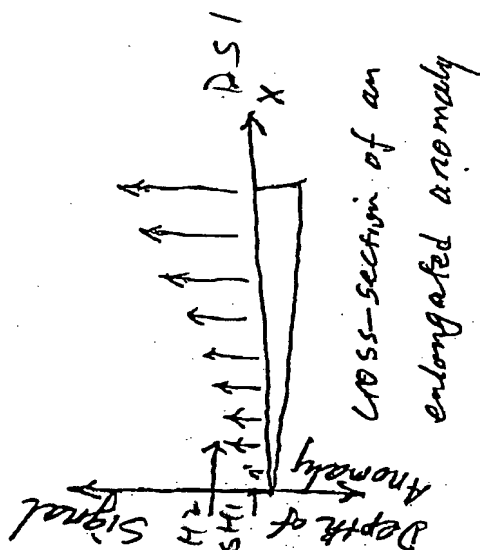


FIG. 7B



Cross-section of  
an non-elongated  
anomaly.

FIG. 9

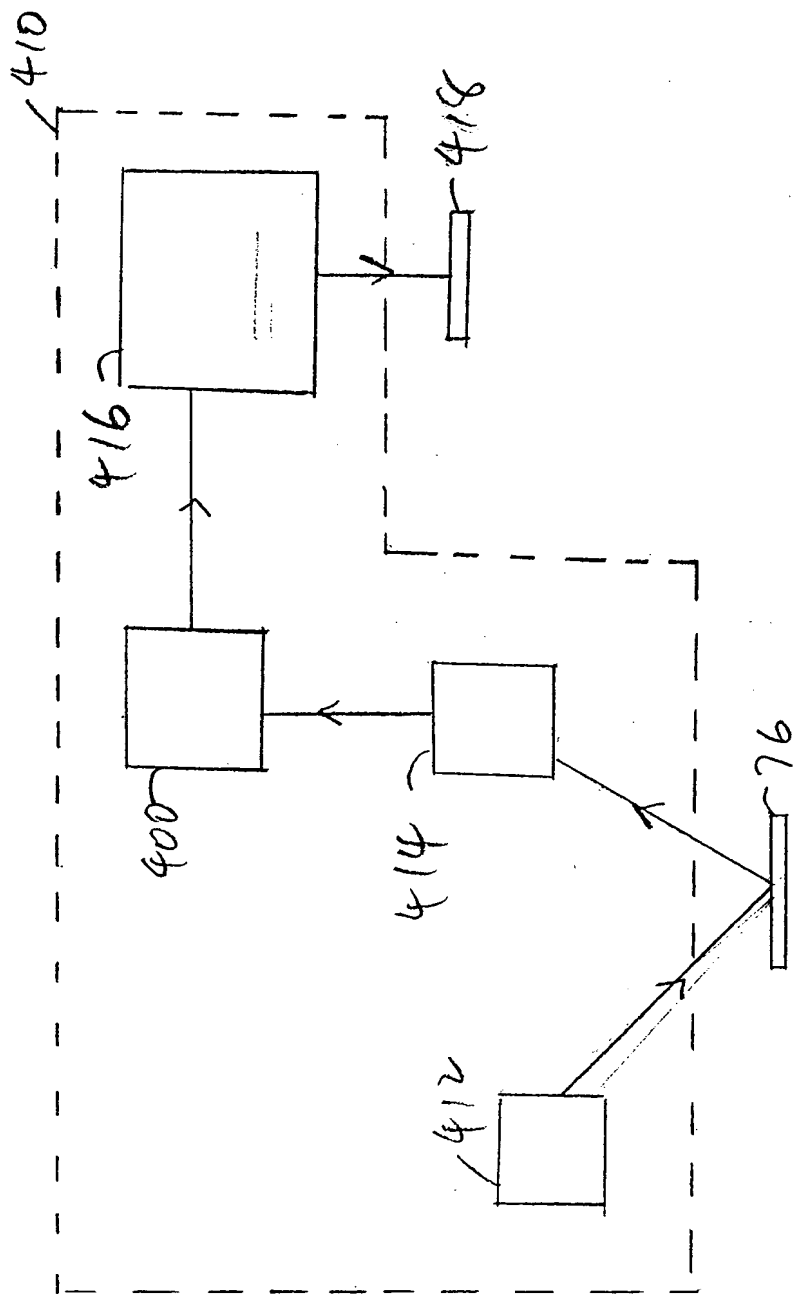


FIG. 10

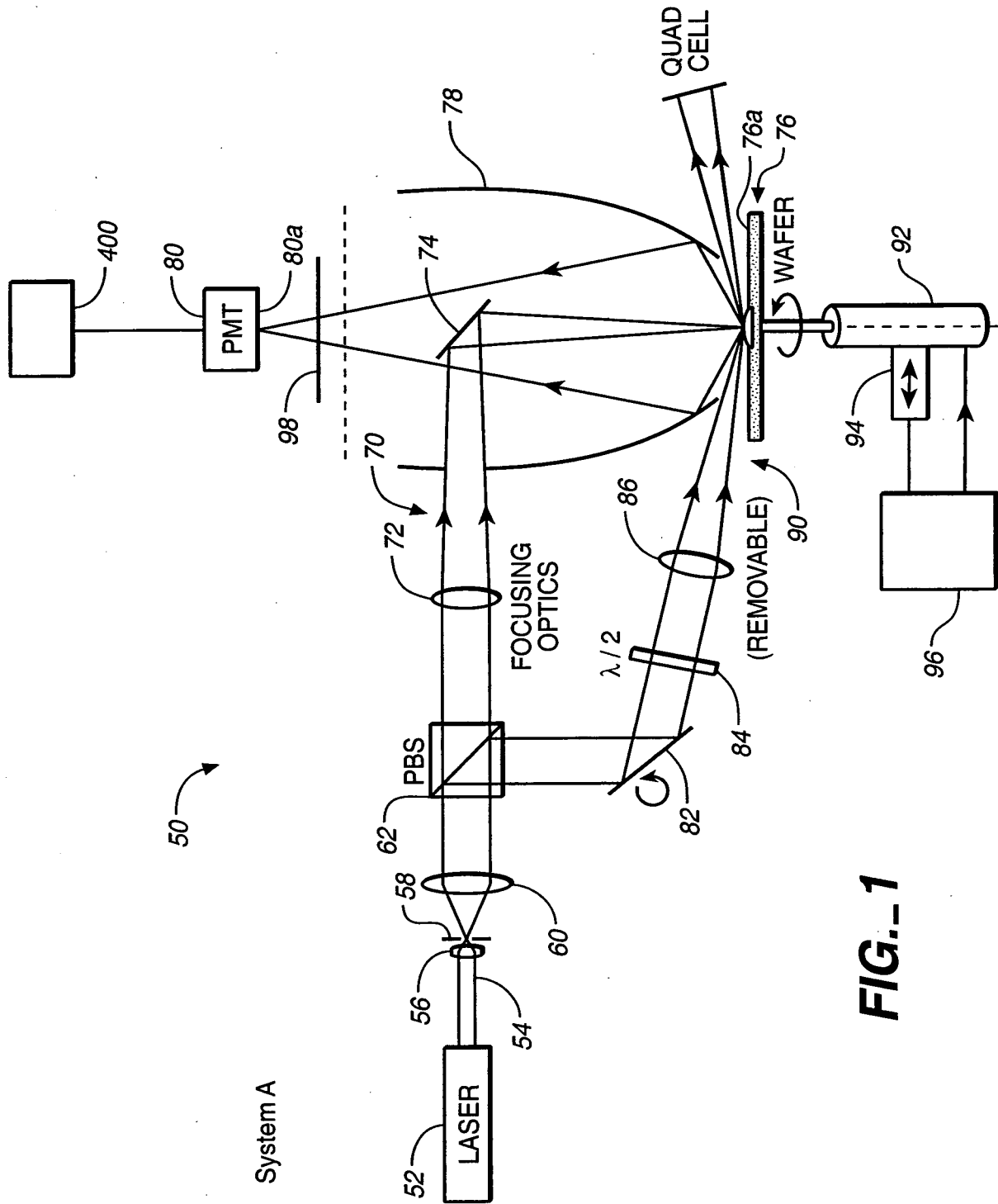
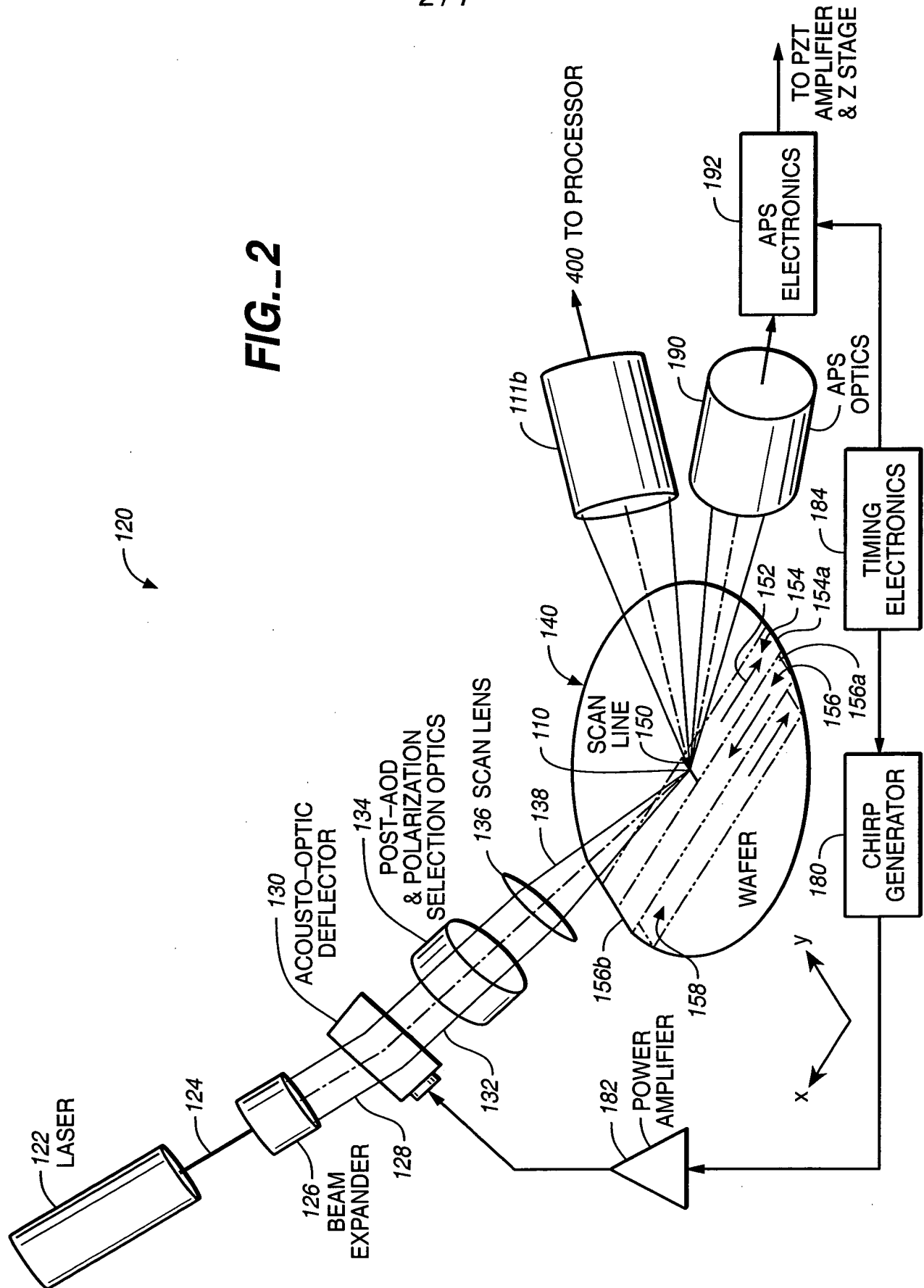
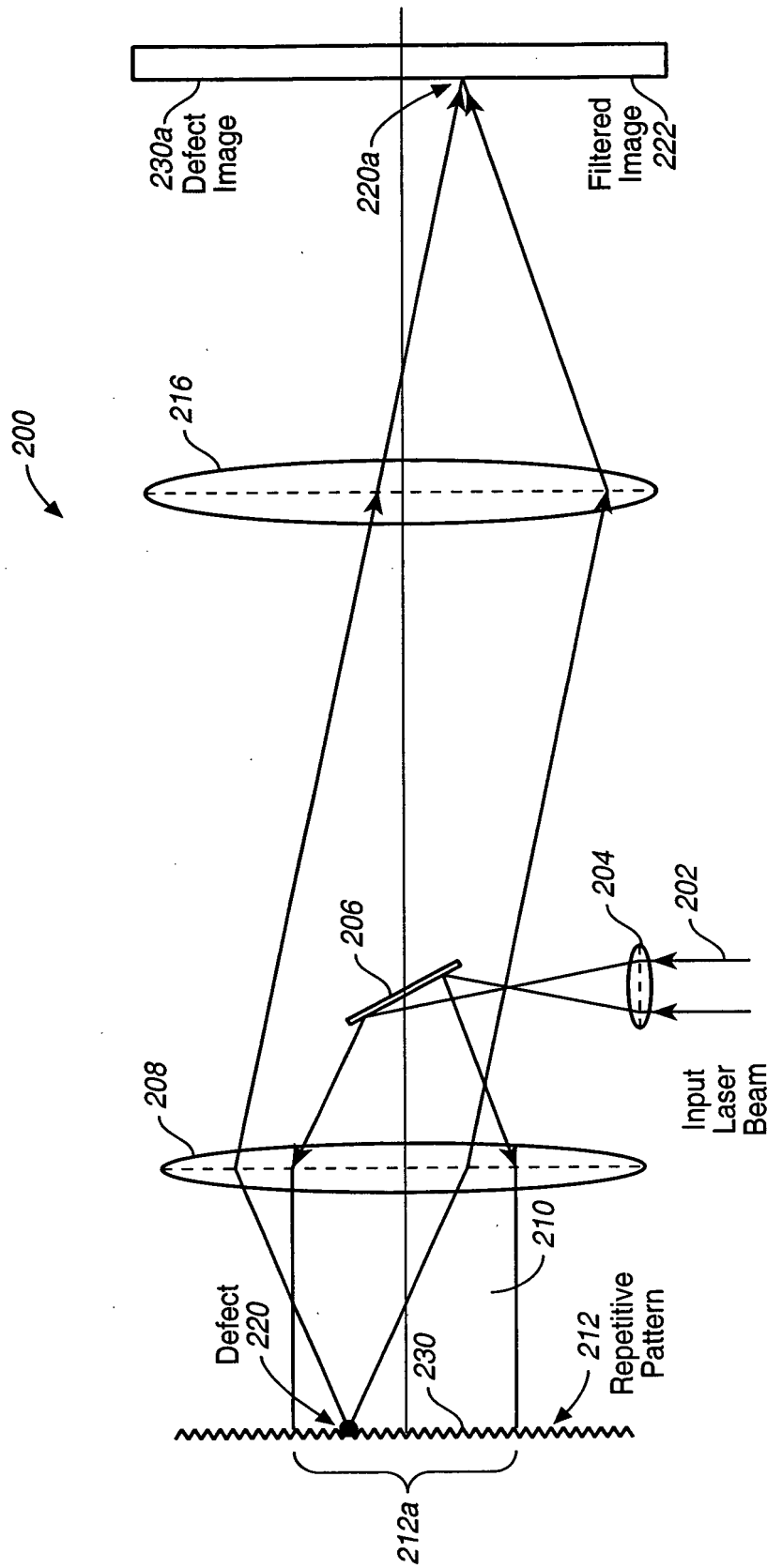




FIG. 2

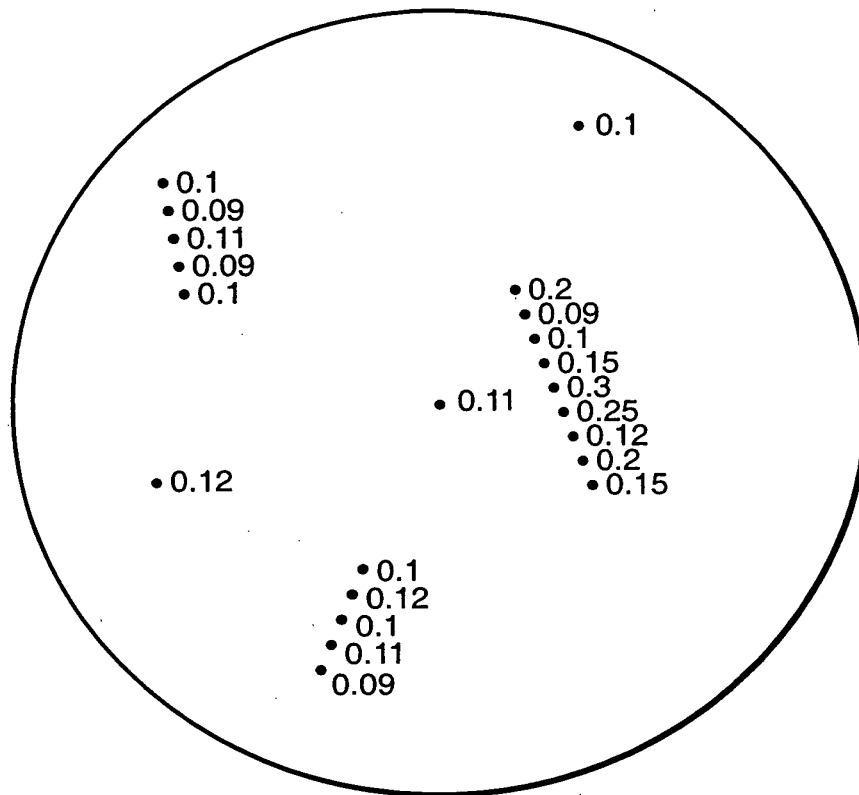




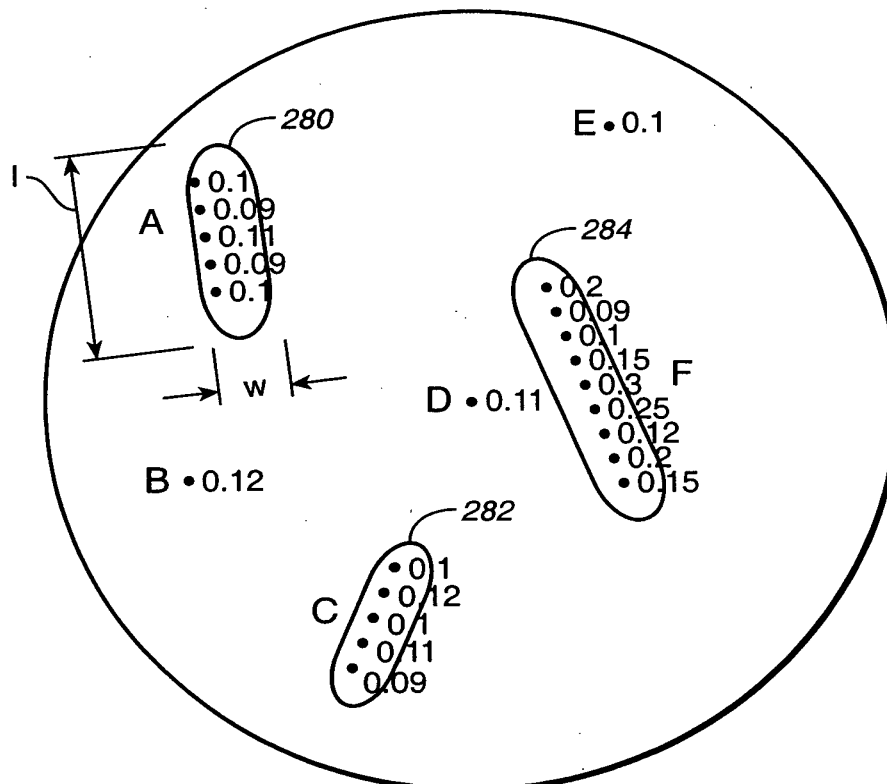
Optical Pattern Filtering Defect Detection

**FIG. 3**

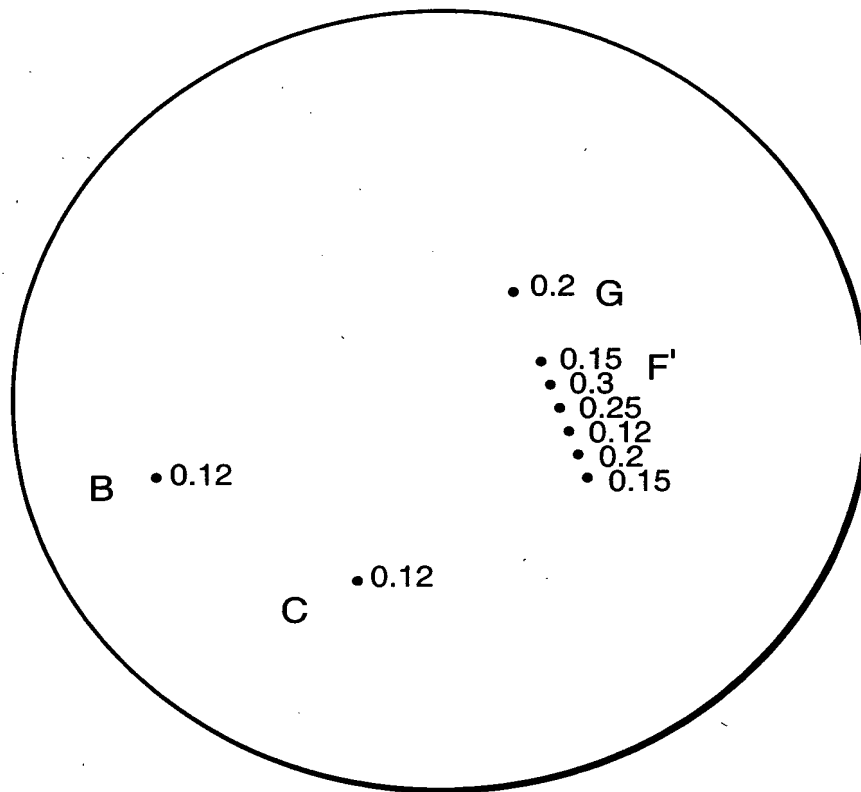
4 / 7

**FIG. 4**

Simulated Distribution of Defects  
After a Scan. Size Indicated in Microns

**FIG. 5**

Initial Clustering in Microscratch Algorithm



Final Output of the Microscratch Algorithm

**FIG.\_6**

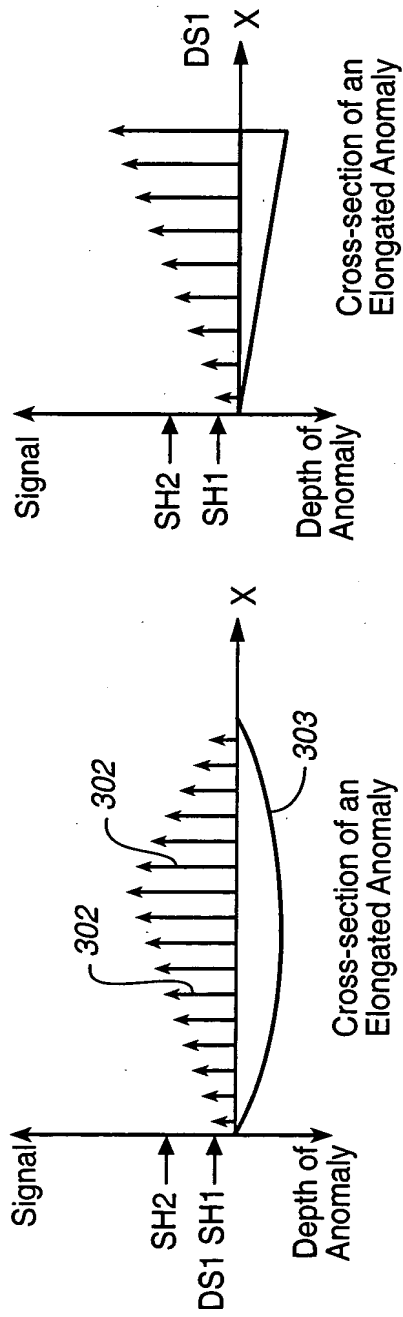


FIG. 7A

FIG. 7B

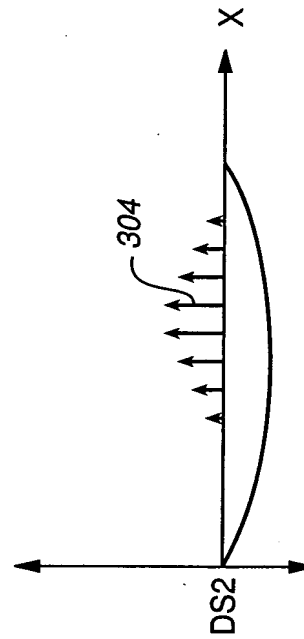


FIG. 8A

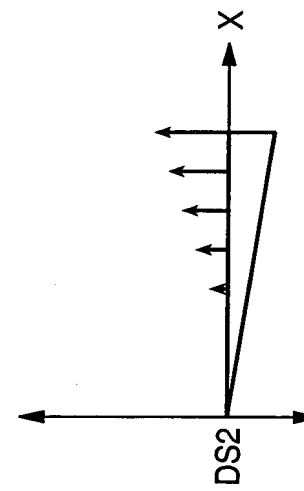


FIG. 8B

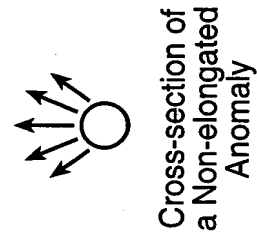


FIG. 9

